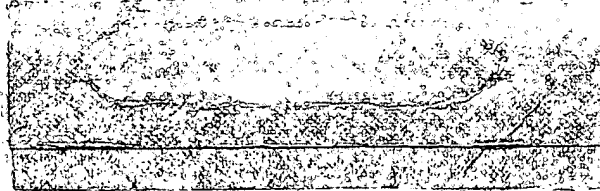


3-20-97/12

	Class	Subclass



PATENT NUMBER

U.S. UTILITY Patent Application

CHIEF OF PARTY <i>Q2</i>	PATENT DATE
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APPLICATION NO. 09/866651	CONT/PRIOR F	CLASS <i>445</i> 25 <i>324</i>	SUBCLASS <i>24</i> <i>750</i>	ART UNIT 2829 <i>2829</i>	EXAMINER <i>SANTIAGO</i> <i>NGUYEN, ANH P.</i>
Masaaki Hiroki					
Device for inspecting element substrates and method of inspection using this device					

PTO-2040
12/99

The term of this patent shall not extend beyond the expiration date of this Patent No. _____

☐ The term of this patent shall not extend beyond the expiration date of this Patent No. _____

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